



Material No.: 5370-05 Batch No.: 0000085172 Manufactured Date: 2014/07/12

Retest Date: 2019/07/11

Certificate of Analysis

Test	Specification	Result
Assay (CH3OH) (by GC)	>= 99.9 %	100.0
Color (APHA)	<= 10	5
Acidity (µeq/g)	<= 0.3	0.2
Alkalinity (µeq/g)	<= 0.1	0.1
Residue after Evaporation	<= 5 ppm	< 1
Water (H2O)(by Karl Fischer titrn)	<= 0.05 %	0.01
Solubility in H ₂ O	Passes Test	PT
Arsenic and Antimony (as As)	<= 10 ppb	< 10
Chloride (CI)	<= 0.2 ppm	< 0.2
Heavy Metals (as Pb)	<= 100 ppb	< 100
Phosphate (PO ₄)	<= 0.3 ppm	< 0.3
Trace Impurities - Aluminum (AI)	<= 50.0 ppb	< 5.0
Trace Impurities – Barium (Ba)	<= 20.0 ppb	< 1.0
Trace Impurities - Boron (B)	<= 10.0 ppb	< 5.0
Trace Impurities - Cadmium (Cd)	<= 20.0 ppb	< 1.0
Trace Impurities - Calcium (Ca)	<= 50.0 ppb	2.9
Trace Impurities – Chromium (Cr)	<= 20.0 ppb	< 1.0
Trace Impurities – Cobalt (Co)	<= 20.0 ppb	< 1.0
Trace Impurities – Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities – Gallium (Ga)	<= 50.0 ppb	< 1.0
Trace Impurities – Germanium (Ge)	<= 50.0 ppb	< 10.0
Trace Impurities – Gold (Au)	<= 20.0 ppb	< 5.0
Trace Impurities – Iron (Fe)	<= 50.0 ppb	< 1.0
Trace Impurities – Lead (Pb)	<= 50.0 ppb	< 10.0

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Trace Impurities – Lithium (Li)	<= 50.0 ppb	< 1.0
Trace Impurities - Magnesium (Mg)	<= 50.0 ppb	< 1.0
Trace Impurities - Manganese (Mn)	<= 10.0 ppb	< 1.0
Trace Impurities - Nickel (Ni)	<= 10.0 ppb	< 3.0
Trace Impurities – Potassium (K)	<= 50.0 ppb	< 10.0
Trace Impurities - Silicon (Si)	<= 50.0 ppb	< 10.0
Trace Impurities - Silver (Ag)	<= 20.0 ppb	< 1.0
Trace Impurities - Sodium (Na)	<= 50.0 ppb	< 5.0
Trace Impurities – Strontium (Sr)	<= 10.0 ppb	< 1.0
Trace Impurities - Tin (Sn)	<= 50.0 ppb	< 10.0
Trace Impurities - Titanium (Ti)	<= 20.0 ppb	< 1.0
Trace Impurities - Zinc (Zn)	<= 50.0 ppb	1.0
Particle Count - 0.5 µm and greater	<= 50 par/ml	3
Particle Count - 1.0 µm and greater	<= 8 par/ml	1

For Microelectronic Use

Reported value is the average of all samples counted for this lot number, with no individual sample value exceeding the specification.

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004 Paris, KY 9001:2008 Mexico City, Mexico 9001:2008 Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003 Gliwice, Poland 9001:2008, 17025:2005 Selangor, Malaysia 9001:2008 Dehradun, India, 9001:2008, 14001:2004, 13485:2003 Mumbai, India, 9001:2008, 17025:2005 Panoli, India 9001:2008

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